



# A Less Biased Evaluation of Out-of-distribution Sample Detectors

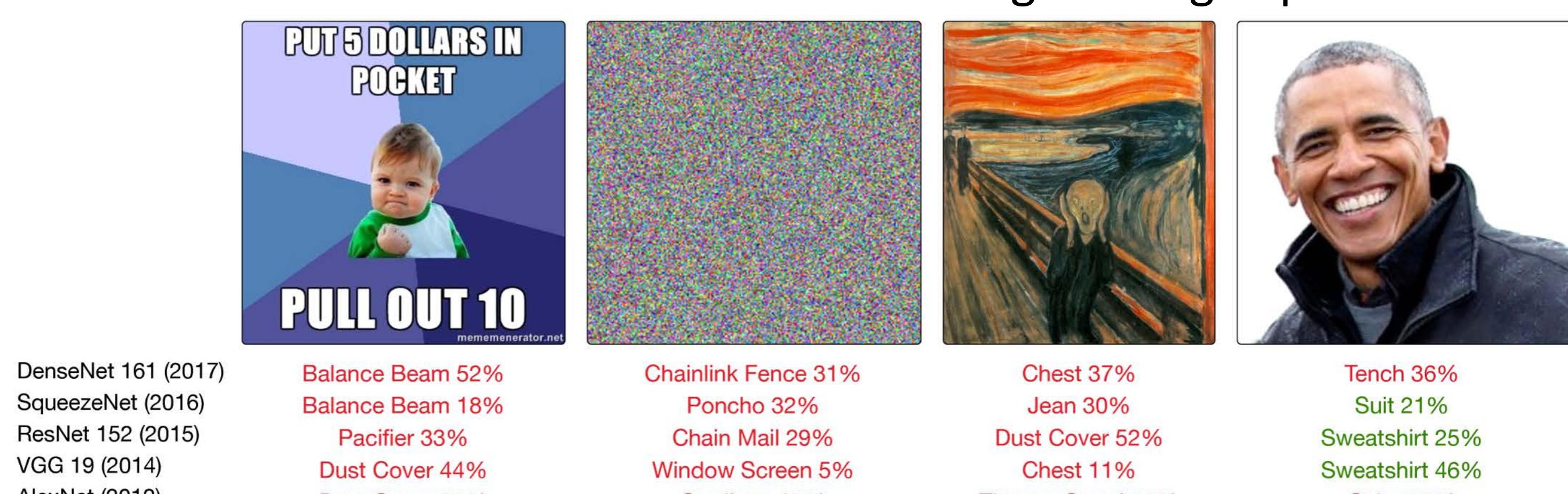
Alireza Shafaei, Mark Schmidt, James Little

University of British Columbia

BMVC 2019

## The Problem

In a typical supervised learning scenario, we *assume* the samples are drawn from a fixed distribution. What can go wrong in practice?

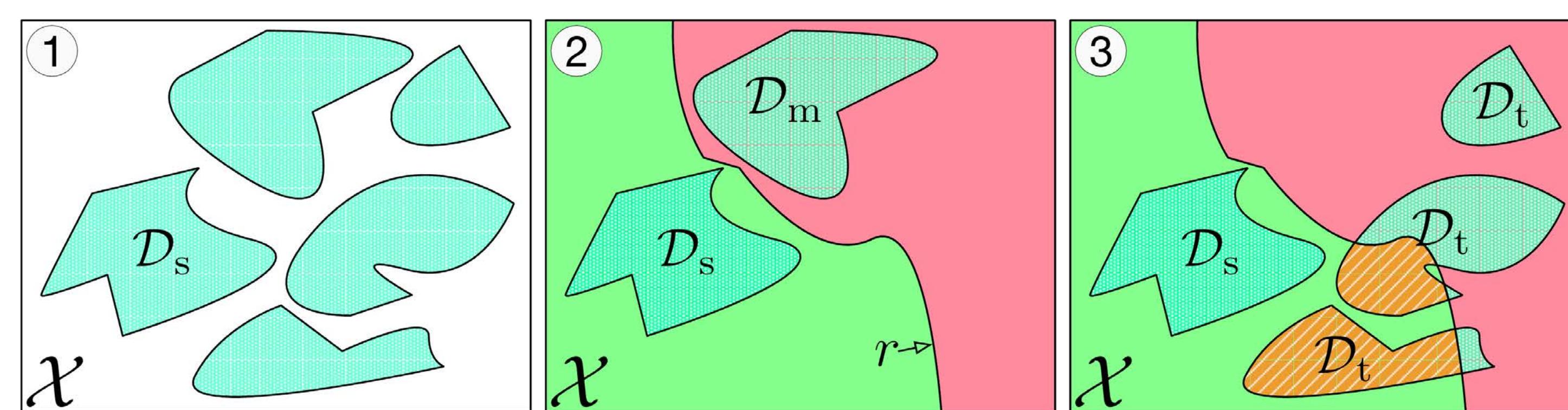


**OOD Detectors** detect the examples where the model cannot give reliable predictions.

- We show that current evaluation strategies over-estimate accuracy.
- We present a **more practical evaluation framework**.
- We show that the state-of-art methods are not reliable in practical scenarios.

## OD-Test: A less biased evaluation strategy

- A binary classifier: *in-distribution* vs. *out-of-distribution* (OOD).
- We do not have access to OOD samples in practice.
- Supervised outlier detection: train a binary classifier on a fixed mixture of outlier and inlier datasets (**two-dataset evaluation**).
- Complex models can easily overfit to two-dataset classifications. Previous work uses a *fixed* mixture of *two low-dimensional* datasets. We show that it yields unreliable optimistic results (see top right).
- A more realistic setup with three datasets (**OD-Test**):  
Given an inlier dataset  $D_s$  and outlier datasets  $D_m$ , and  $D_t$ .
  - Observe a clean  $D_s$ .
  - Learn a binary reject function  $r$  on the mixture of  $D_s$  and  $D_m$ .
  - Test the reject function on the mixture of  $D_s$  and  $D_t$ .
 Repeat over different outlier datasets to obtain a reliable estimate of performance on  $D_s$ .



## Experimental Setup

### Methods.

- Uncertainty:** MC-Dropout [1], DeepEnsemble [2].
- Density estimation:** PixelCNN++ [3].
- Open-set recognition:** OpenMax [4].
- Deep learning literature:** ODIN [5], Probability Threshold.
- Outlier/Anomaly detection:** K-NN, Reconstruction-based.
- Other:** K-NN on Autoencoder and VAE latent representations, SVM on logits, K-way logistic regression loss, direct binary classification.

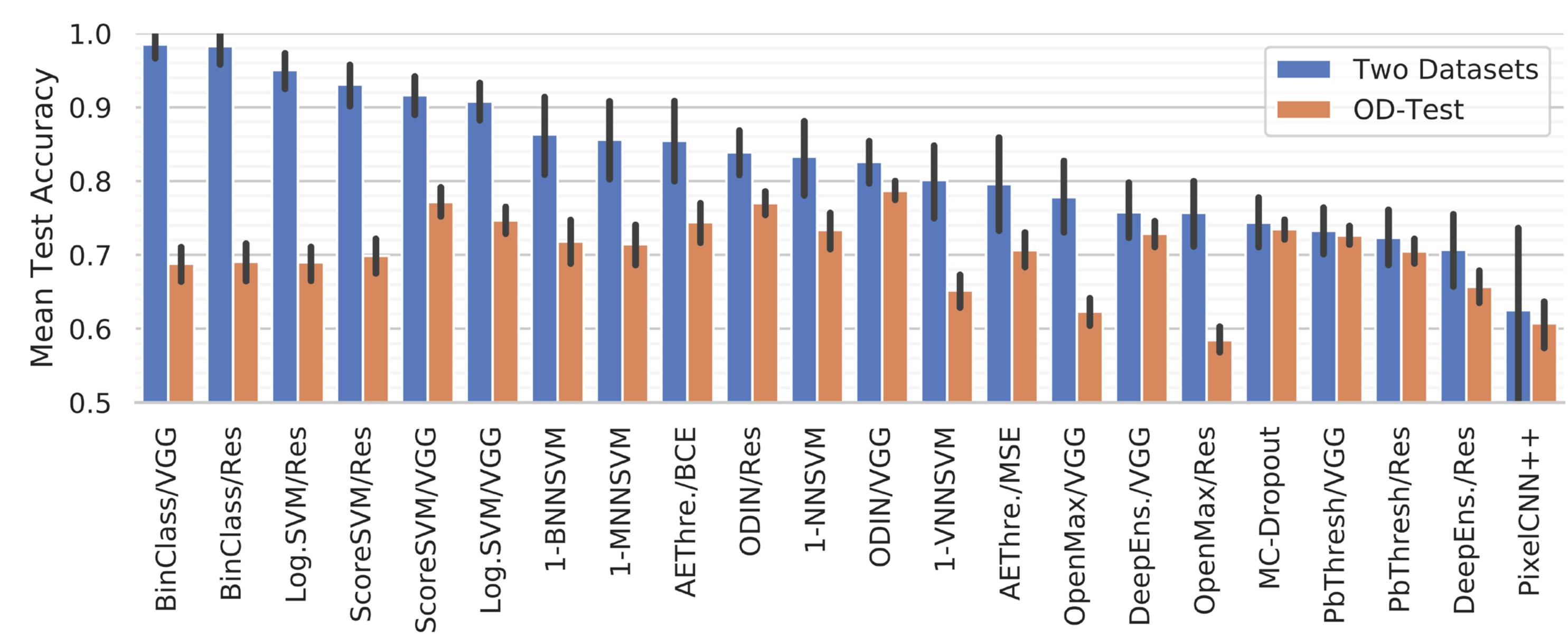
### Models.

- VGG-16
- Resnet-50

### Datasets.

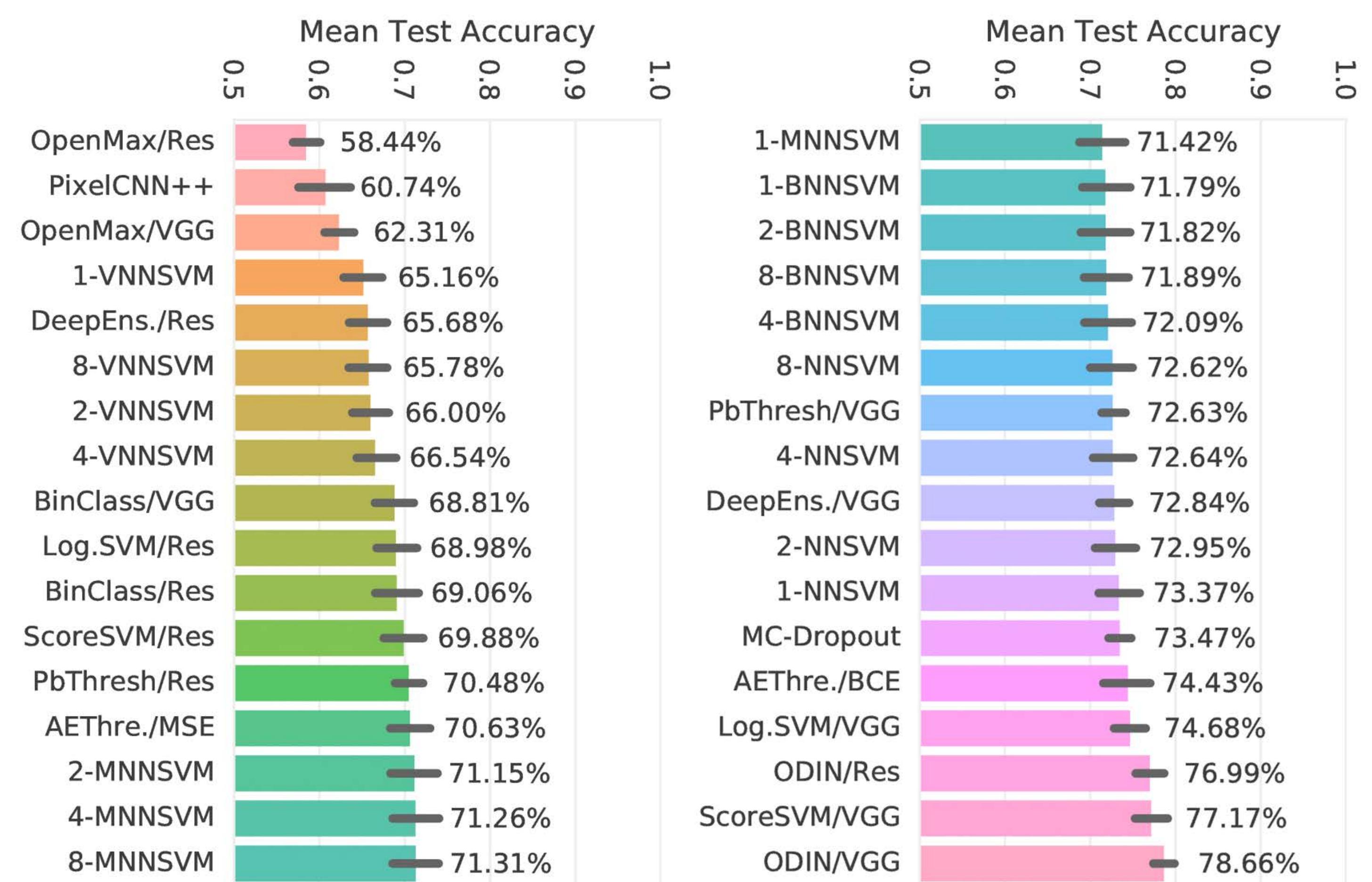
- MNIST
- FashionMNIST
- NotMNIST
- CIFAR10
- CIFAR100
- STL10
- TinyImagenet
- Uniform Noise
- Gaussian Noise

## Two-dataset evaluation vs. OD-test (n = 46/bar, 308/bar)

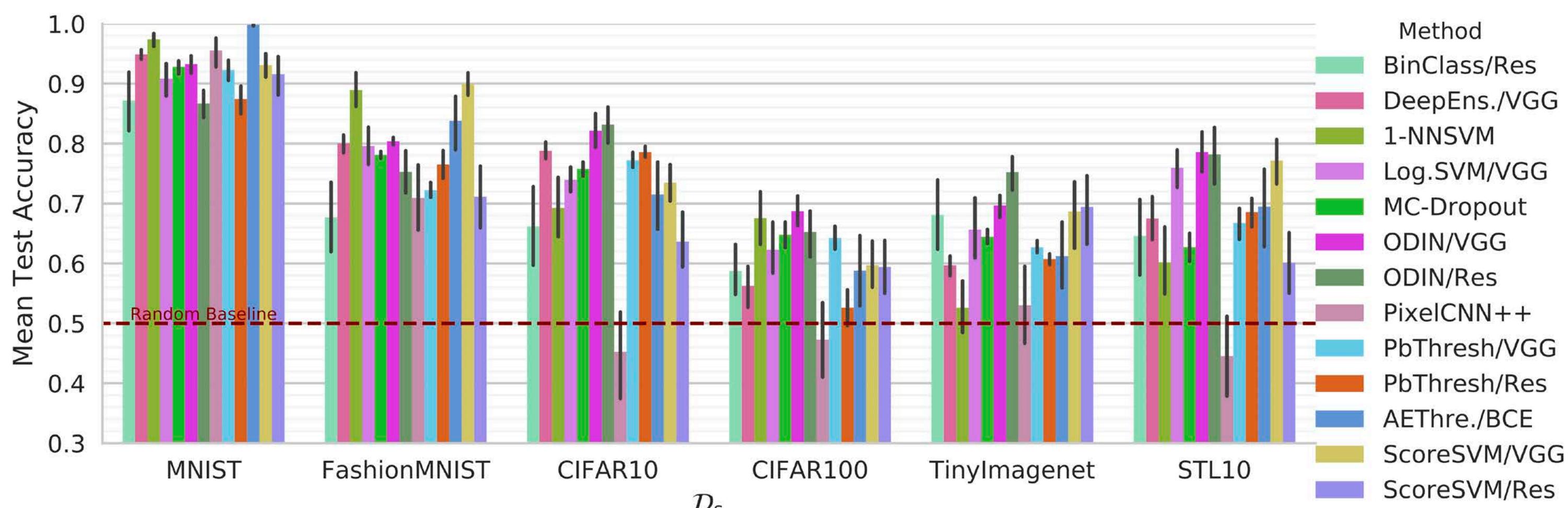


A two-dataset evaluation scheme can be too optimistic in identifying the best available method.

## Mean test accuracy, averaging over $D_s$ , $D_m$ , $D_t$ (n = 308/bar)



## Mean test accuracy per source dataset $D_s$ (n = 54/bar)

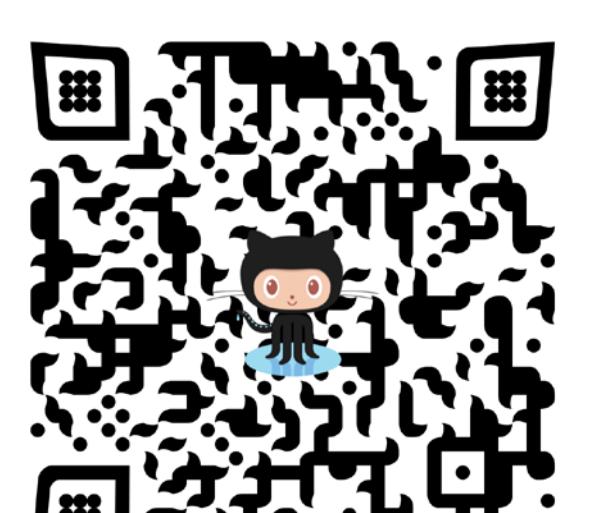


## A Short Summary of Results

- A two-dataset evaluation can make us too optimistic.
- Simpler/cheaper data mining approaches work as well as the recently proposed methods in low-dimensional settings.
- None of the methods work well on high-dimensional data.
- VGG-16 is better than Resnet-50 for this task, even though the Resnet model has a higher image classification accuracy.
- For a more reliable assessment, future work should use **OD-test** instead of two-dataset evaluations.

## Selected References

- [1] Y. Gal and Z. Ghahramani, "Dropout as a Bayesian Approximation: Representing Model Uncertainty in Deep Learning," in *ICML*, 2016.
- [2] B. Lakshminarayanan, A. Pritzel, and C. Blundell, "Simple and Scalable Predictive Uncertainty Estimation using Deep Ensembles," in *NIPS*, 2017.
- [3] T. Salimans, A. Karpathy, X. Chen, and D. P. Kingma, "Pixelcnn++: Improving the pixelcnn with discretized logistic mixture likelihood and other modifications," *ICLR*, 2017.
- [4] A. Bendale and T. E. Boult, "Towards Open Set Deep Networks," in *CVPR*, 2016.
- [5] S. Liang, Y. Li, and R. Srikanth, "Enhancing The Reliability of Out-of-distribution Image Detection in Neural Networks," *ICLR*, 2018.



Replicate the results on GitHub  
<https://github.com/ashafaei/OD-test>